

May 2001

# **FQP13N06**

## **60V N-Channel MOSFET**

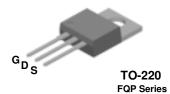
#### **General Description**

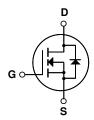
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters, high efficiency switching for power management in portable and battery operated products.

#### **Features**

- 13A, 60V,  $R_{DS(on)}$  = 0.135 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 5.8 nC)
- Low Crss (typical 15 pF)
- Fast switching
- · 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





## **Absolute Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQP13N06	Units
V <sub>DSS</sub>	Drain-Source Voltage		60	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25	°C)	13	Α
	- Continuous (T <sub>C</sub> = 100°C)		9.2	Α
$I_{DM}$	Drain Current - Pulsed	(Note 1)	52	Α
$V_{GSS}$	Gate-Source Voltage		± 25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	85	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	13	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	4.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		45	W
	- Derate above 25°C		0.3	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes,		300	°C
'L	1/8" from case for 5 seconds		300	

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.35	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		0.06		V/°C
I <sub>DSS</sub>	Zarra Cata Valtana Duain Comunant	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 48 V, T <sub>C</sub> = 150°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6.5 A		0.105	0.135	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_D = 6.5 \text{ A}$ (Note 4)		5.1		S
Dynam	ic Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		240	310	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		90	120	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			15	20	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V 20 V I 6 F A		5	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 30 \text{ V}, I_{D} = 6.5 \text{ A},$ $R_{G} = 25 \Omega$		25	60	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1 1 1 G - 20 32		8	25	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		15	40	ns
Qg	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 13 \text{ A},$		5.8	7.5	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		2.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		2.5		nC
	anno Diodo Obomodonistico o	ad Marrianova Datinara				
Drain-S	Source Diode Characteristics at Maximum Continuous Drain-Source Did	<u>~</u>			13	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				52	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 13 A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 13 \text{ A,}$		39		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dl_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		40		nC
II	Hororoo Hoodyory Orlange	- 1 · - 1 · - 1 · - 1 · - 1 · · · · · ·		70		110

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 590μH, I<sub>AS</sub> = 13A, V<sub>DD</sub> = 25V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  13A, di/dt  $\leq$  300A/us, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

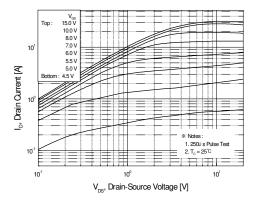


Figure 1. On-Region Characteristics

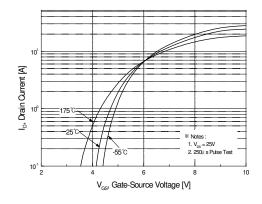


Figure 2. Transfer Characteristics

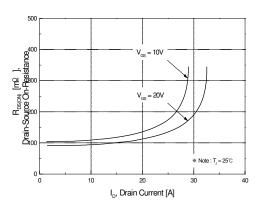


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

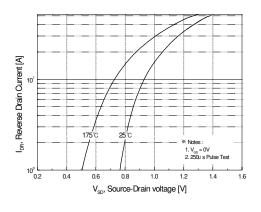


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

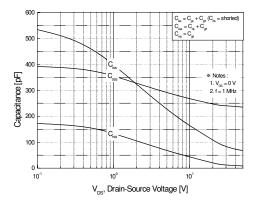


Figure 5. Capacitance Characteristics

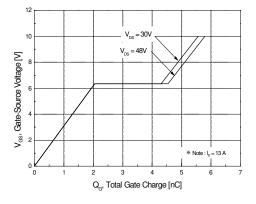
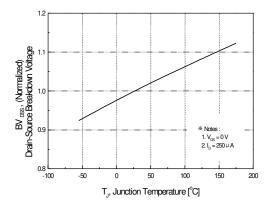


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



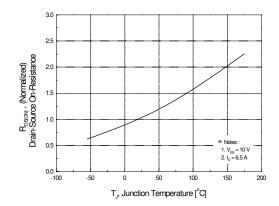
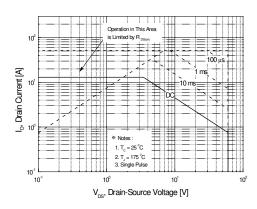


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



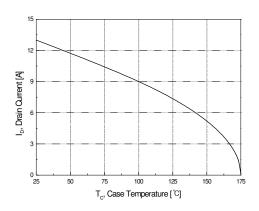


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

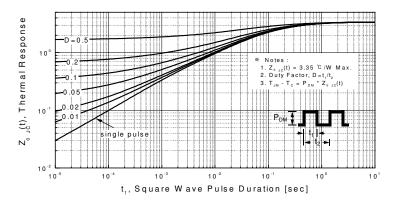
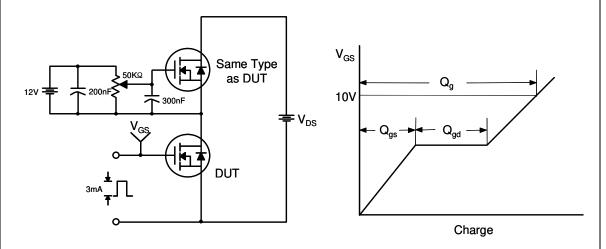


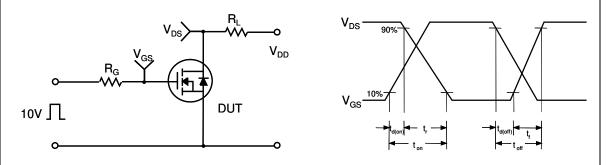
Figure 11. Transient Thermal Response Curve

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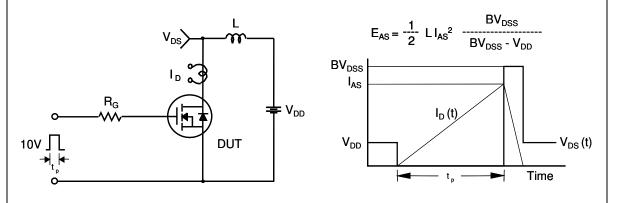
## **Gate Charge Test Circuit & Waveform**



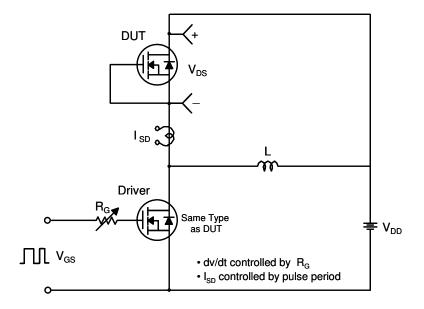
## **Resistive Switching Test Circuit & Waveforms**

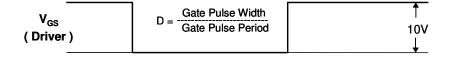


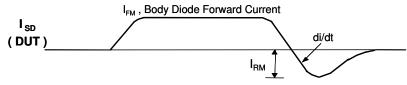
## **Unclamped Inductive Switching Test Circuit & Waveforms**



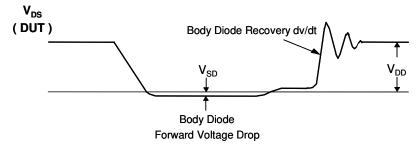
## Peak Diode Recovery dv/dt Test Circuit & Waveforms

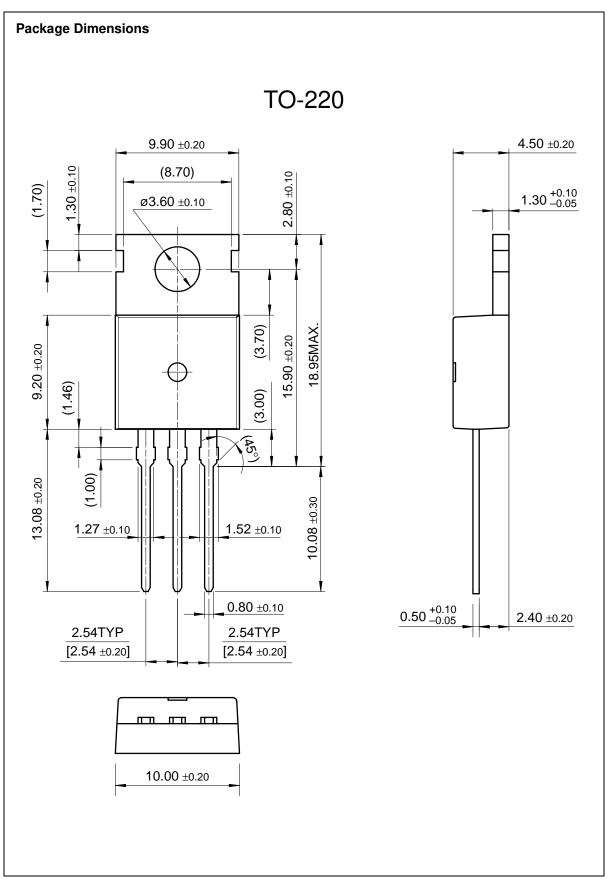






Body Diode Reverse Current





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